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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	260
Total RAM Bits	-
Number of I/O	34
Number of Gates	10000
Voltage - Supply	1.14V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	48-VFQFN Exposed Pad
Supplier Device Package	48-QFN (6x6)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/agln010v2-qng48i

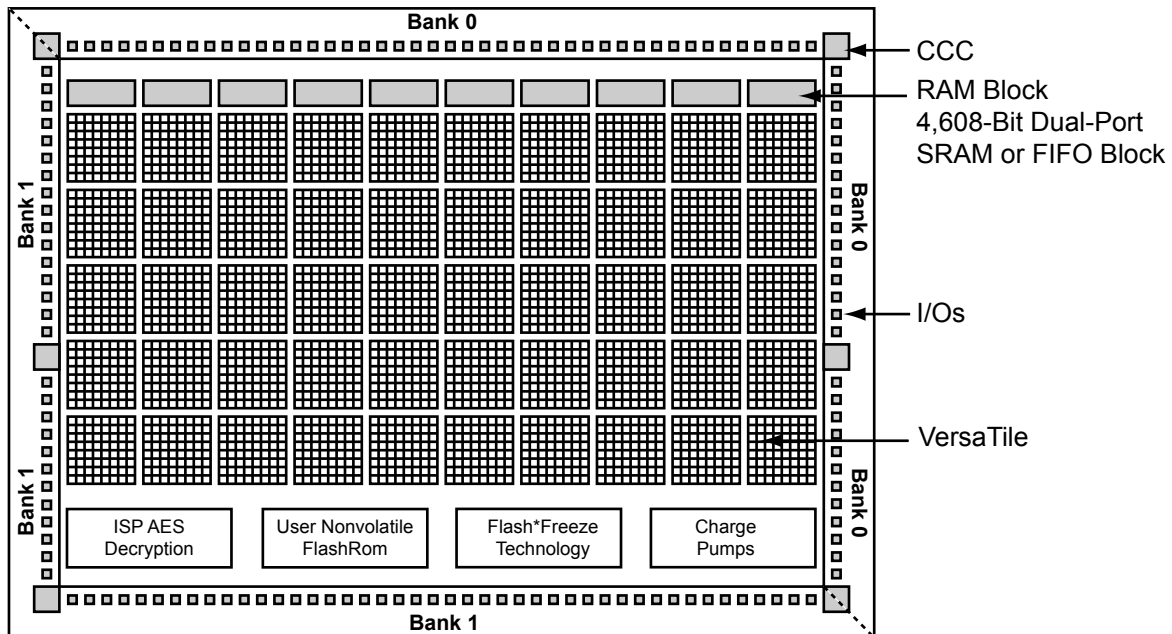


Figure 1-3 • IGLOO Device Architecture Overview with Two I/O Banks (AGLN060, AGLN125)

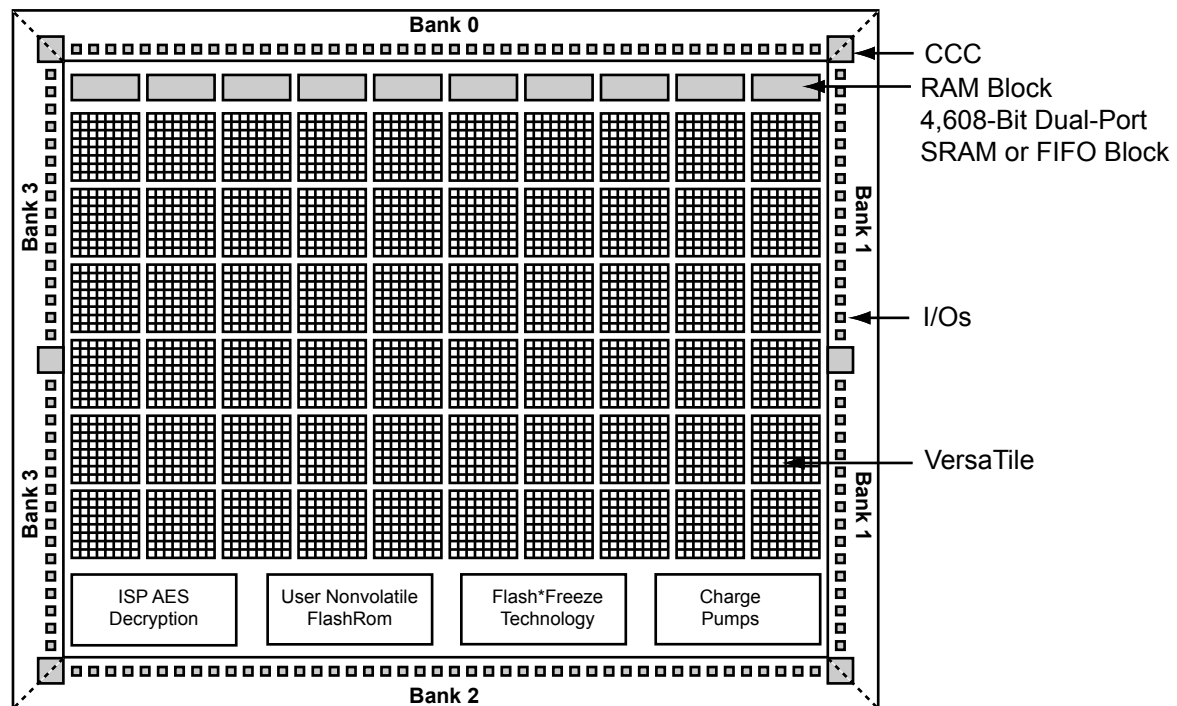


Figure 1-4 • IGLOO Device Architecture Overview with Four I/O Banks (AGLN250)

2 – IGLOO nano DC and Switching Characteristics

General Specifications

The Z feature grade does not support the enhanced nano features of Schmitt trigger input, Flash*Freeze bus hold (hold previous I/O state in Flash*Freeze mode), cold-sparing, and hot-swap I/O capability. Refer to "IGLOO nano Ordering Information" on page IV for more information.

Operating Conditions

Stresses beyond those listed in Table 2-1 may cause permanent damage to the device.

Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Absolute Maximum Ratings are stress ratings only; functional operation of the device at these or any other conditions beyond those listed under the Recommended Operating Conditions specified in Table 2-2 on page 2-2 is not implied.

Table 2-1 • Absolute Maximum Ratings

Symbol	Parameter	Limits	Units
VCC	DC core supply voltage	–0.3 to 1.65	V
VJTAG	JTAG DC voltage	–0.3 to 3.75	V
VPUMP	Programming voltage	–0.3 to 3.75	V
VCCPLL	Analog power supply (PLL)	–0.3 to 1.65	V
VCCI	DC I/O buffer supply voltage	–0.3 to 3.75	V
VI ¹	I/O input voltage	–0.3 V to 3.6 V	V
T _{STG} ²	Storage temperature	–65 to +150	°C
T _J ²	Junction temperature	+125	°C

Notes:

1. The device should be operated within the limits specified by the datasheet. During transitions, the input signal may undershoot or overshoot according to the limits shown in Table 2-4 on page 2-3.
2. For flash programming and retention maximum limits, refer to Table 2-3 on page 2-2, and for recommended operating limits, refer to Table 2-2 on page 2-2.

Table 2-2 • Recommended Operating Conditions ¹

Symbol	Parameter		Extended Commercial	Industrial	Units
T _J	Junction temperature		–20 to + 85 ²	–40 to +100 ²	°C
VCC	1.5 V DC core supply voltage ³		1.425 to 1.575	1.425 to 1.575	V
	1.2 V–1.5 V wide range core voltage ^{4,5}		1.14 to 1.575	1.14 to 1.575	V
VJTAG	JTAG DC voltage		1.4 to 3.6	1.4 to 3.6	V
VPUMP ⁶	Programming voltage	Programming mode	3.15 to 3.45	3.15 to 3.45	V
		Operation	0 to 3.6	0 to 3.6	V
VCCPLL ⁷	Analog power supply (PLL)	1.5 V DC core supply voltage ³	1.425 to 1.575	1.425 to 1.575	V
		1.2 V–1.5 V wide range core supply voltage ⁴	1.14 to 1.575	1.14 to 1.575	V
VCCI and VMV ^{8,9}	1.2 V DC supply voltage ⁴		1.14 to 1.26	1.14 to 1.26	V
	1.2 V DC wide range supply voltage ⁴		1.14 to 1.575	1.14 to 1.575	V
	1.5 V DC supply voltage		1.425 to 1.575	1.425 to 1.575	V
	1.8 V DC supply voltage		1.7 to 1.9	1.7 to 1.9	V
	2.5 V DC supply voltage		2.3 to 2.7	2.3 to 2.7	V
	3.3 V DC supply voltage		3.0 to 3.6	3.0 to 3.6	V
	3.3 V DC wide range supply voltage ¹⁰		2.7 to 3.6	2.7 to 3.6	V

Notes:

1. All parameters representing voltages are measured with respect to GND unless otherwise specified.
2. Default Junction Temperature Range in the Libero SoC software is set to 0°C to +70°C for commercial, and –40°C to +85°C for industrial. To ensure targeted reliability standards are met across the full range of junction temperatures, Microsemi recommends using custom settings for temperature range before running timing and power analysis tools. For more information regarding custom settings, refer to the New Project Dialog Box in the Libero Online Help.
3. For IGLOO® nano V5 devices
4. For IGLOO nano V2 devices only, operating at VCCI ≥ VCC
5. IGLOO nano V5 devices can be programmed with the VCC core voltage at 1.5 V only. IGLOO nano V2 devices can be programmed with the VCC core voltage at 1.2 V (with FlashPro4 only) or 1.5 V. If you are using FlashPro3 and want to do in-system programming using 1.2 V, please contact the factory.
6. V_{PUMP} can be left floating during operation (not programming mode).
7. VCCPLL pins should be tied to VCC pins. See the "Pin Descriptions" chapter for further information.
8. VMV pins must be connected to the corresponding VCCI pins. See the Pin Descriptions chapter of the IGLOO nano FPGA Fabric User's Guide for further information.
9. The ranges given here are for power supplies only. The recommended input voltage ranges specific to each I/O standard are given in Table 2-21 on page 2-19. VCCI should be at the same voltage within a given I/O bank.
10. 3.3 V wide range is compliant to the JESD8-B specification and supports 3.0 V VCCI operation.

Table 2-3 • Flash Programming Limits – Retention, Storage, and Operating Temperature¹

Product Grade	Programming Cycles	Program Retention (biased/unbiased)	Maximum Storage Temperature T _{STG} (°C) ²	Maximum Operating Junction Temperature T _J (°C) ²
Commercial	500	20 years	110	100
Industrial	500	20 years	110	100

Notes:

1. This is a stress rating only; functional operation at any condition other than those indicated is not implied.
2. These limits apply for program/data retention only. Refer to Table 2-1 on page 2-1 and Table 2-2 for device operating conditions and absolute limits.

PLL Behavior at Brownout Condition

Microsemi recommends using monotonic power supplies or voltage regulators to ensure proper power-up behavior. Power ramp-up should be monotonic at least until VCC and VCCPLX exceed brownout activation levels (see Figure 2-1 and Figure 2-2 on page 2-5 for more details).

When PLL power supply voltage and/or VCC levels drop below the VCC brownout levels ($0.75\text{ V} \pm 0.25\text{ V}$ for V5 devices, and $0.75\text{ V} \pm 0.2\text{ V}$ for V2 devices), the PLL output lock signal goes LOW and/or the output clock is lost. Refer to the "Brownout Voltage" section in the "Power-Up/Down Behavior of Low Power Flash Devices" chapter of the *IGLOO nano FPGA Fabric User's Guide* for information on clock and lock recovery.

Internal Power-Up Activation Sequence

1. Core
2. Input buffers
3. Output buffers, after 200 ns delay from input buffer activation

To make sure the transition from input buffers to output buffers is clean, ensure that there is no path longer than 100 ns from input buffer to output buffer in your design.

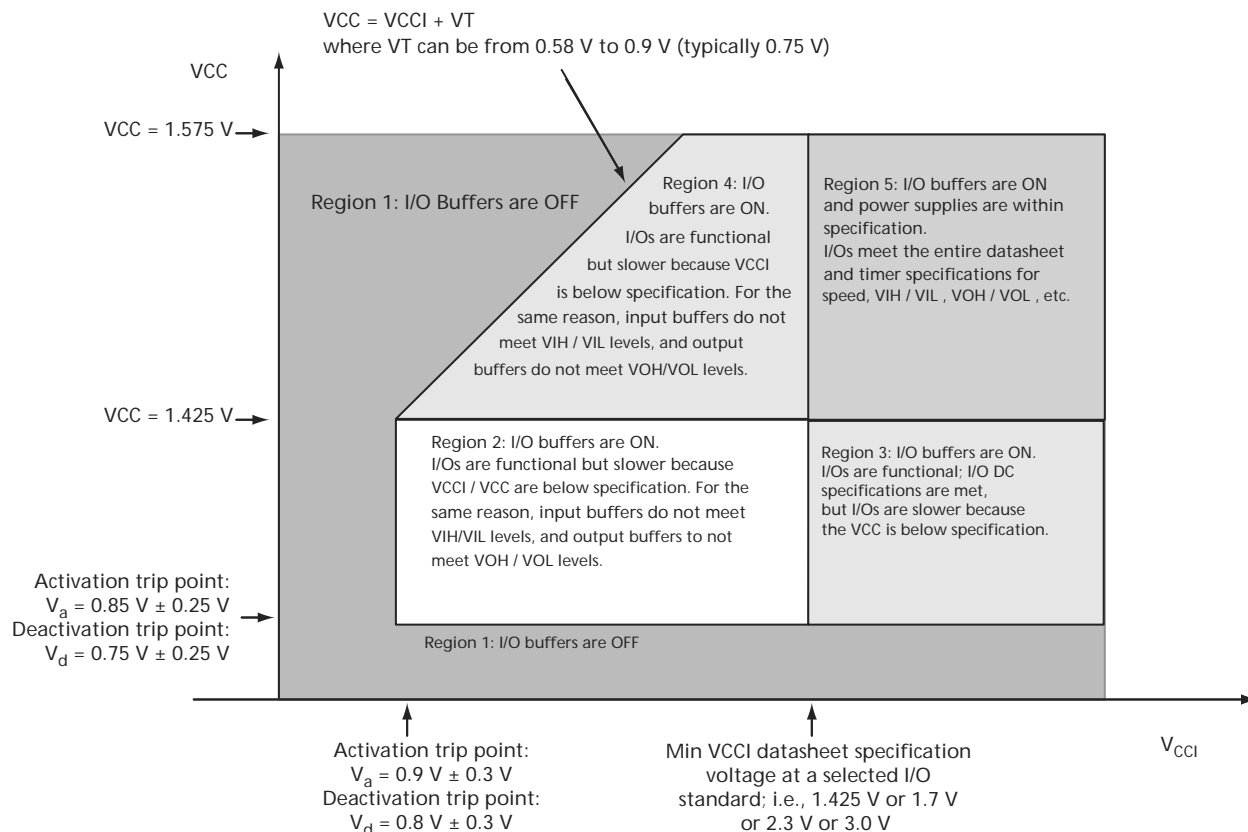


Figure 2-1 • V5 Devices – I/O State as a Function of VCCI and VCC Voltage Levels

Table 2-7 • Temperature and Voltage Derating Factors for Timing Delays (normalized to $T_J = 70^\circ\text{C}$, $V_{CC} = 1.14\text{ V}$)
For IGLOO nano V2, 1.2 V DC Core Supply Voltage

Array Voltage VCC (V)	Junction Temperature ($^\circ\text{C}$)						
	-40°C	-20°C	0°C	25°C	70°C	85°C	100°C
1.14	0.968	0.974	0.979	0.991	1.000	1.006	1.009
1.2	0.863	0.868	0.873	0.884	0.892	0.898	0.901
1.26	0.792	0.797	0.801	0.811	0.819	0.824	0.827

Calculating Power Dissipation

Quiescent Supply Current

Quiescent supply current (I_{DD}) calculation depends on multiple factors, including operating voltages (V_{CC} , V_{CCI} , and V_{JTAG}), operating temperature, system clock frequency, and power mode usage. Microsemi recommends using the Power Calculator and SmartPower software estimation tools to evaluate the projected static and active power based on the user design, power mode usage, operating voltage, and temperature.

Table 2-8 • Power Supply State per Mode

Modes/Power Supplies	Power Supply Configurations				
	VCC	VCCPLL	VCCI	VJTAG	VPUMP
Flash*Freeze	On	On	On	On	On/off/floating
Sleep	Off	Off	On	Off	Off
Shutdown	Off	Off	Off	Off	Off
No Flash*Freeze	On	On	On	On	On/off/floating

Note: Off: Power Supply level = 0 V

Table 2-9 • Quiescent Supply Current (I_{DD}) Characteristics, IGLOO nano Flash*Freeze Mode*

	Core Voltage	AGLN010	AGLN015	AGLN020	AGLN060	AGLN125	AGLN250	Units
Typical (25°C)	1.2 V	1.9	3.3	3.3	8	13	20	μA
	1.5 V	5.8	6	6	10	18	34	μA

Note: * I_{DD} includes VCC, VPUMP, VCCI, VCCPLL, and VMV currents. Values do not include I/O static contribution, which is shown in Table 2-13 on page 2-9 through Table 2-14 on page 2-9 and Table 2-15 on page 2-10 through Table 2-18 on page 2-11 (PDC6 and PDC7).

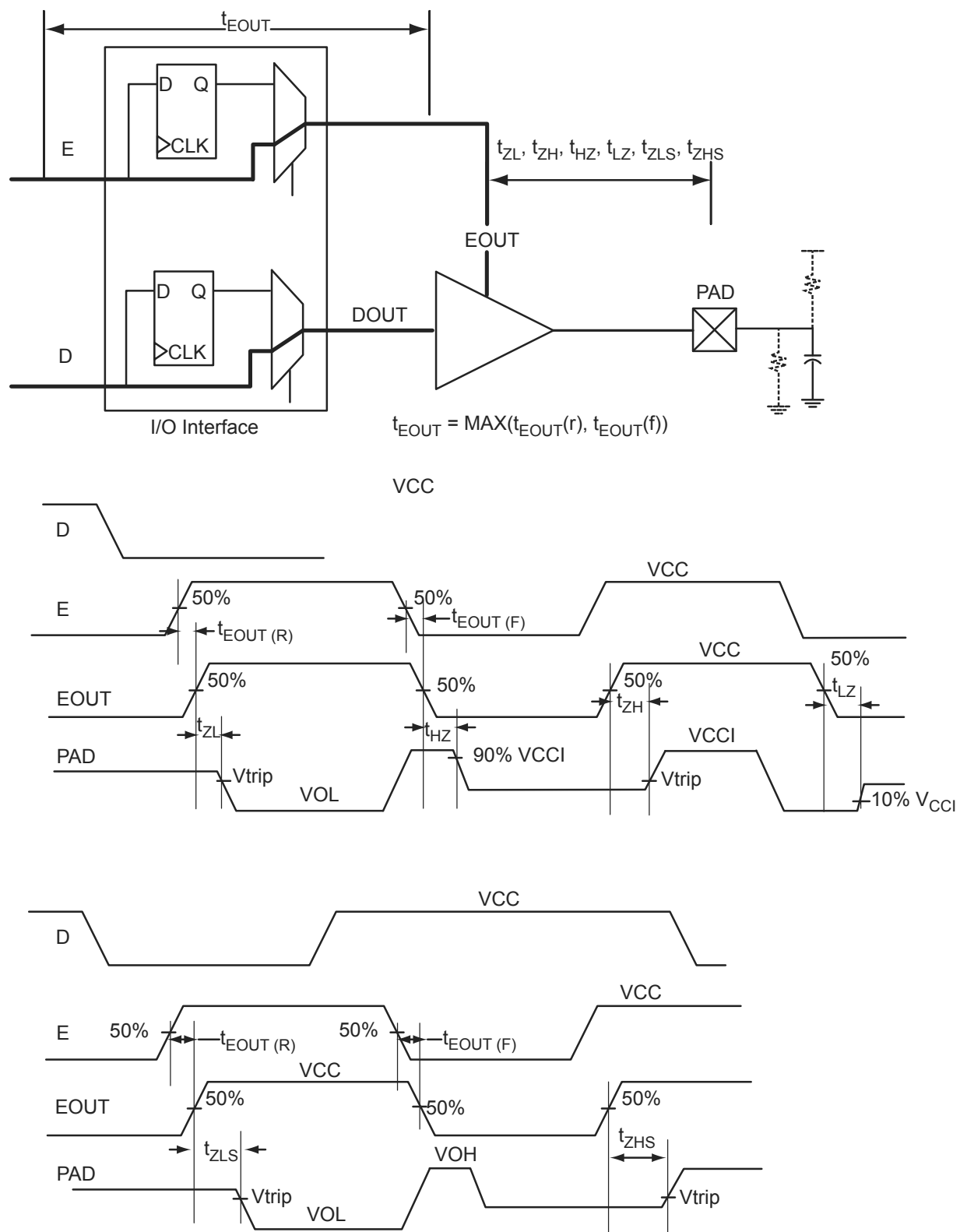


Figure 2-6 • Tristate Output Buffer Timing Model and Delays (example)

Timing Characteristics

Applies to 1.5 V DC Core Voltage

Table 2-36 • 3.3 V LVTTL / 3.3 V LVCMOS Low Slew – Applies to 1.5 V DC Core Voltage
Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 3.0 V

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{PYS}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	Units
2 mA	STD	0.97	3.52	0.19	0.86	1.16	0.66	3.59	3.42	1.75	1.90	ns
4 mA	STD	0.97	3.52	0.19	0.86	1.16	0.66	3.59	3.42	1.75	1.90	ns
6 mA	STD	0.97	2.90	0.19	0.86	1.16	0.66	2.96	2.83	1.98	2.29	ns
8 mA	STD	0.97	2.90	0.19	0.86	1.16	0.66	2.96	2.83	1.98	2.29	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

Table 2-37 • 3.3 V LVTTL / 3.3 V LVCMOS High Slew – Applies to 1.5 V DC Core Voltage
Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 3.0 V

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{PYS}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	Units
2 mA	STD	0.97	2.16	0.19	0.86	1.16	0.66	2.20	1.80	1.75	1.99	ns
4 mA	STD	0.97	2.16	0.19	0.86	1.16	0.66	2.20	1.80	1.75	1.99	ns
6 mA	STD	0.97	1.79	0.19	0.86	1.16	0.66	1.83	1.45	1.98	2.38	ns
8 mA	STD	0.97	1.79	0.19	0.86	1.16	0.66	1.83	1.45	1.98	2.38	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

3.3 V LVCMOS Wide Range

Table 2-40 • Minimum and Maximum DC Input and Output Levels for LVCMOS 3.3 V Wide Range

3.3 V LVCMOS Wide Range ¹	Equivalent Software Default Drive Strength Option ⁴	VIL		VIH		VOL	VOH	IOL	I _{OH}	IIL ²	IIH ³
Drive Strength		Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	μA	μA	μA ⁵	μA ⁵
100 μA	2 mA	−0.3	0.8	2	3.6	0.2	VCCI − 0.2	100	100	10	10
100 μA	4 mA	−0.3	0.8	2	3.6	0.2	VCCI − 0.2	100	100	10	10
100 μA	6 mA	−0.3	0.8	2	3.6	0.2	VCCI − 0.2	100	100	10	10
100 μA	8 mA	−0.3	0.8	2	3.6	0.2	VCCI − 0.2	100	100	10	10

Notes:

1. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V Wide Range, as specified in the JEDEC JESD8-B specification.
2. I_{IL} is the input leakage current per I/O pin over recommended operating conditions where $-0.3 < V_{IN} < V_{IL}$.
3. I_{IH} is the input leakage current per I/O pin over recommended operating conditions where $V_{IH} < V_{IN} < V_{CCI}$. Input current is larger when operating outside recommended ranges.
4. The minimum drive strength for any LVCMOS 3.3 V software configuration when run in wide range is $\pm 100 \mu A$. Drive strength displayed in the software is supported for normal range only. For a detailed I/V curve, refer to the IBIS models.
5. Currents are measured at 85°C junction temperature.
6. Software default selection is highlighted in gray.

Output Register

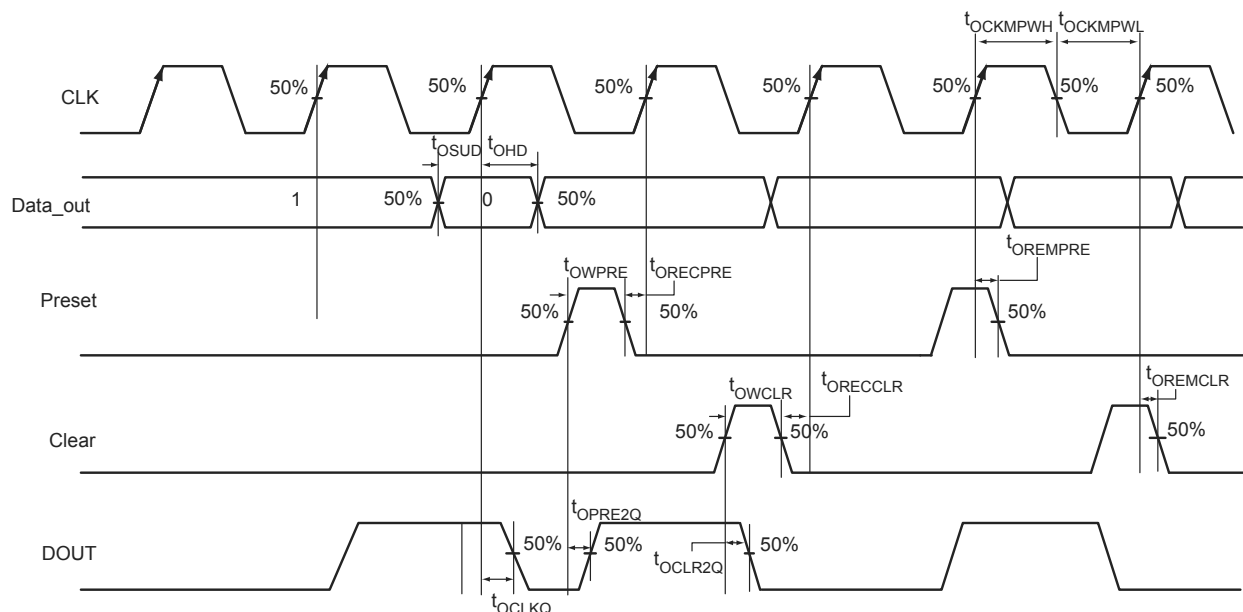


Figure 2-15 • Output Register Timing Diagram

Timing Characteristics

1.5 V DC Core Voltage

Table 2-74 • Output Data Register Propagation Delays
Commercial-Case Conditions: $T_J = 70^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$

Parameter	Description	Std.	Units
t_{OCLKQ}	Clock-to-Q of the Output Data Register	1.00	ns
t_{OSUD}	Data Setup Time for the Output Data Register	0.51	ns
t_{OHD}	Data Hold Time for the Output Data Register	0.00	ns
t_{OCLR2Q}	Asynchronous Clear-to-Q of the Output Data Register	1.34	ns
t_{OPRE2Q}	Asynchronous Preset-to-Q of the Output Data Register	1.34	ns
t_{OREMCLR}	Asynchronous Clear Removal Time for the Output Data Register	0.00	ns
t_{ORECCLR}	Asynchronous Clear Recovery Time for the Output Data Register	0.24	ns
t_{OREMPRE}	Asynchronous Preset Removal Time for the Output Data Register	0.00	ns
t_{ORECPRE}	Asynchronous Preset Recovery Time for the Output Data Register	0.24	ns
t_{OWCLR}	Asynchronous Clear Minimum Pulse Width for the Output Data Register	0.19	ns
t_{OWPRE}	Asynchronous Preset Minimum Pulse Width for the Output Data Register	0.19	ns
t_{OCKMPWH}	Clock Minimum Pulse Width HIGH for the Output Data Register	0.31	ns
t_{OCKMPWL}	Clock Minimum Pulse Width LOW for the Output Data Register	0.28	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

Output DDR Module

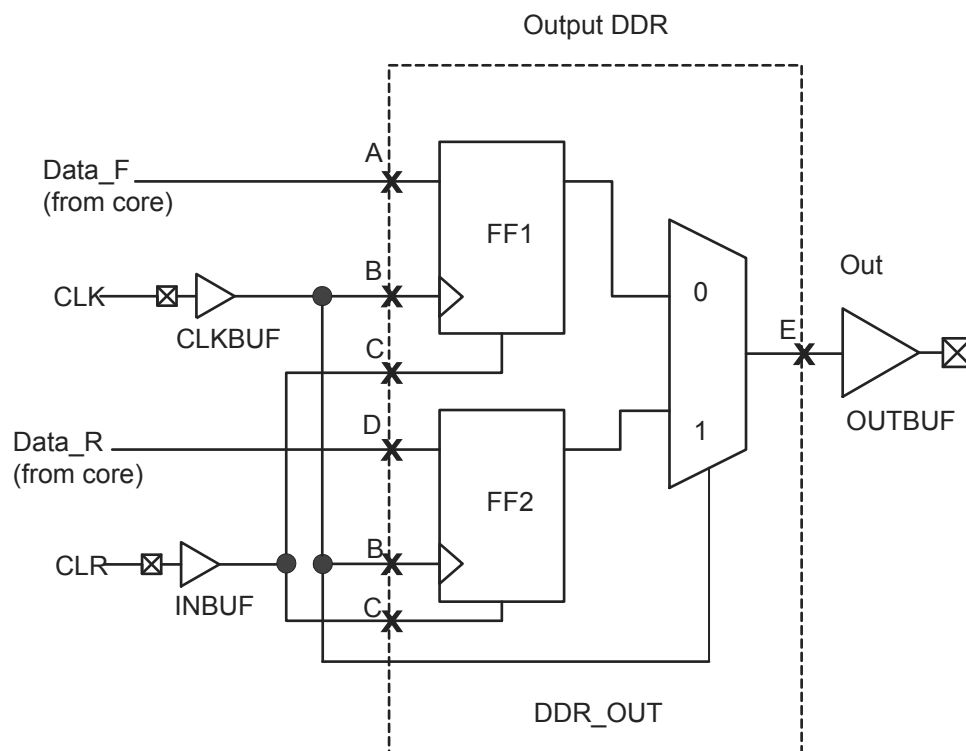


Figure 2-19 • Output DDR Timing Model

Table 2-81 • Parameter Definitions

Parameter Name	Parameter Definition	Measuring Nodes (from, to)
t_{DDROCLKQ}	Clock-to-Out	B, E
$t_{\text{DDROCLR2Q}}$	Asynchronous Clear-to-Out	C, E
$t_{\text{DDROREMCLR}}$	Clear Removal	C, B
$t_{\text{DDRORECCLR}}$	Clear Recovery	C, B
t_{DDROSUD1}	Data Setup Data_F	A, B
t_{DDROSUD2}	Data Setup Data_R	D, B
t_{DDROHD1}	Data Hold Data_F	A, B
t_{DDROHD2}	Data Hold Data_R	D, B

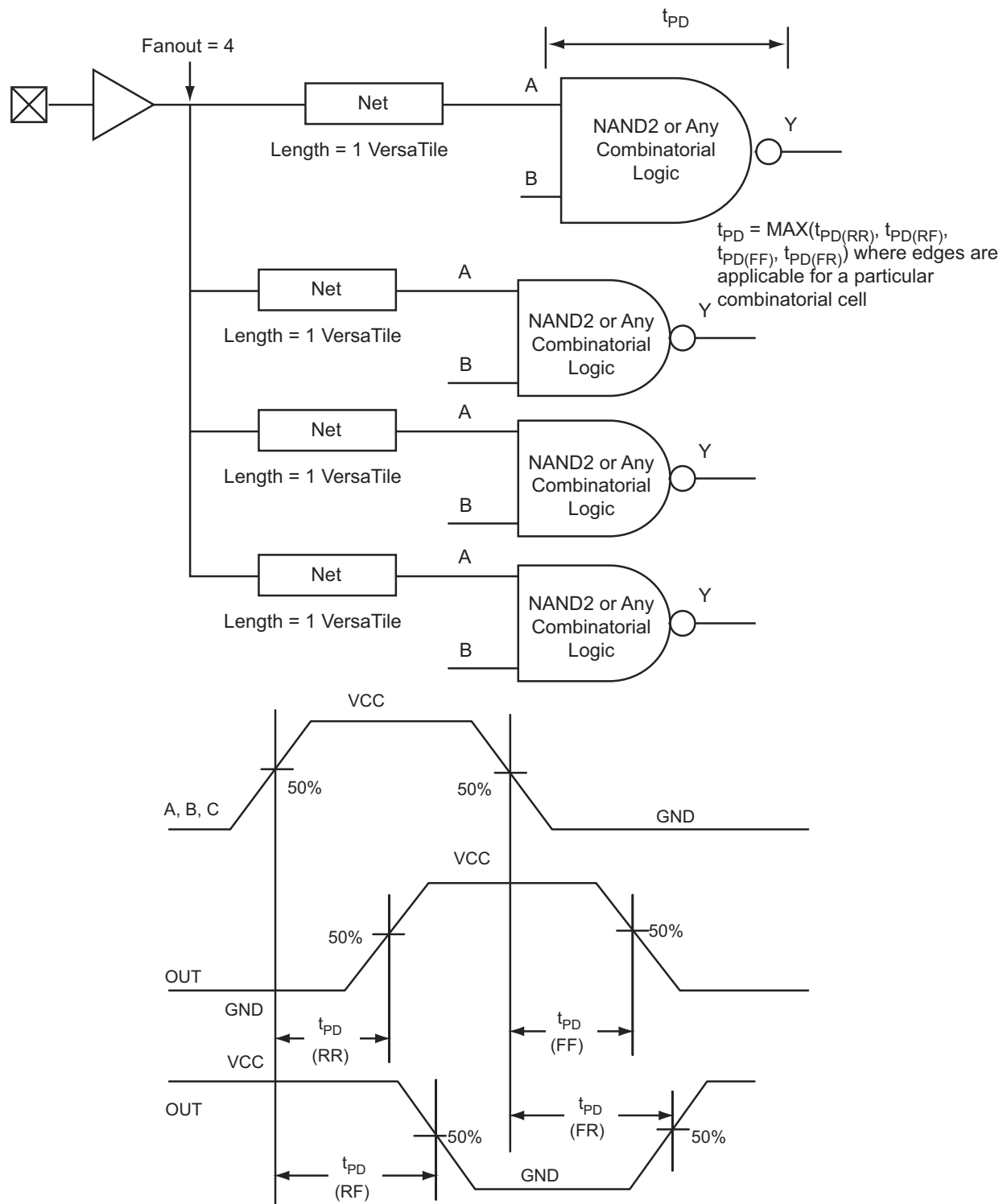


Figure 2-22 • Timing Model and Waveforms

VersaTile Specifications as a Sequential Module

The IGLOO nano library offers a wide variety of sequential cells, including flip-flops and latches. Each has a data input and optional enable, clear, or preset. In this section, timing characteristics are presented for a representative sample from the library. For more details, refer to the *IGLOO, ProASIC3, SmartFusion and Fusion Macro Library Guide for Software v10.1*.

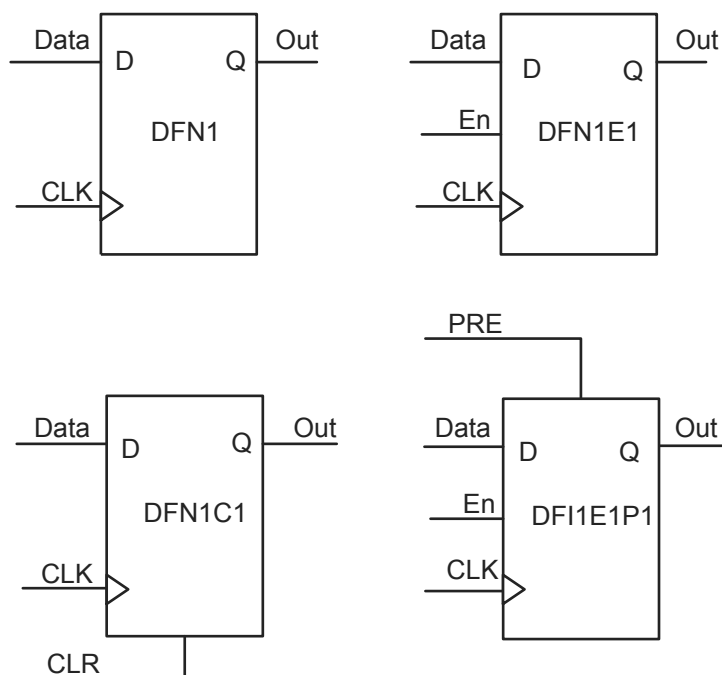


Figure 2-23 • Sample of Sequential Cells

Timing Waveforms

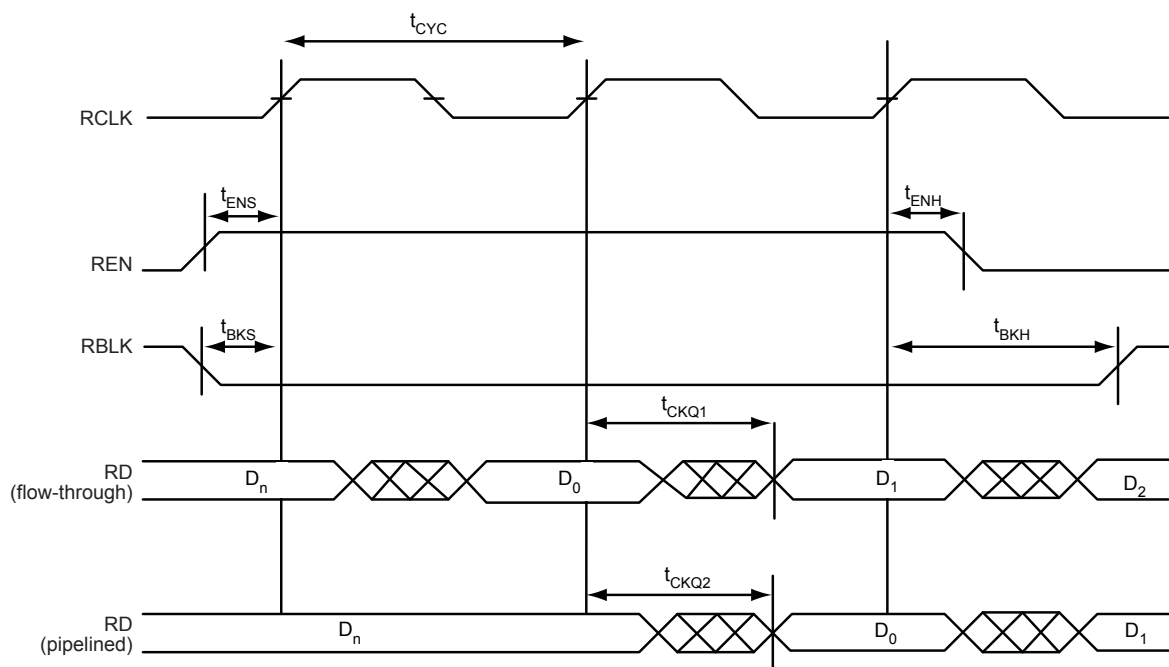


Figure 2-34 • FIFO Read

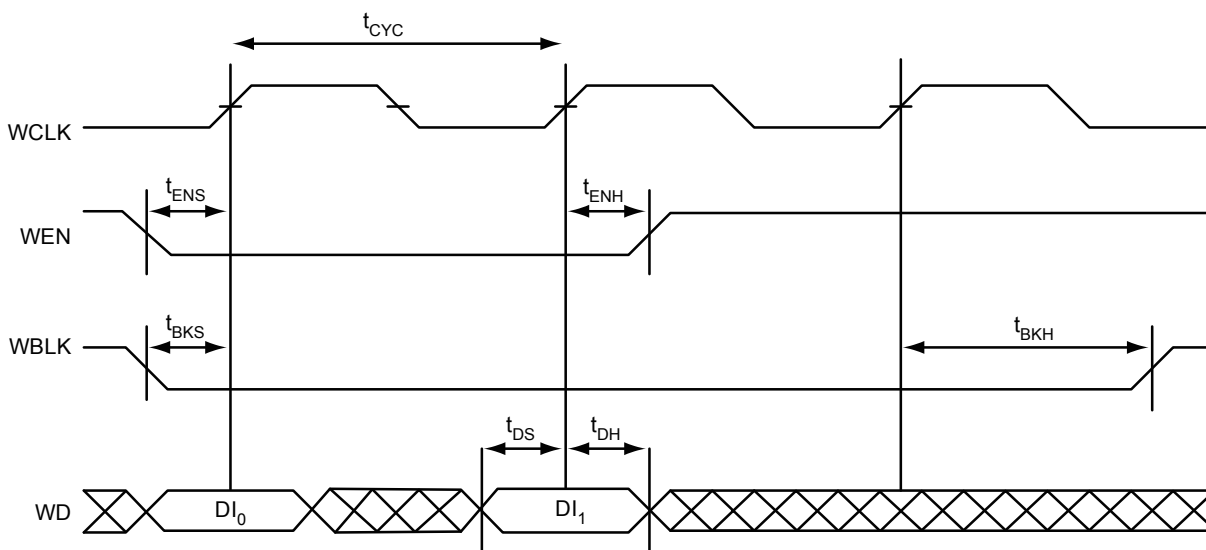


Figure 2-35 • FIFO Write

Timing Characteristics

1.5 V DC Core Voltage

Table 2-106 • FIFO

Worst Commercial-Case Conditions: $T_J = 70^{\circ}\text{C}$, $V_{CC} = 1.425\text{ V}$

Parameter	Description	Std.	Units
t_{ENS}	REN, WEN Setup Time	1.66	ns
t_{ENH}	REN, WEN Hold Time	0.13	ns
t_{BKS}	BLK Setup Time	0.30	ns
t_{BKH}	BLK Hold Time	0.00	ns
t_{DS}	Input Data (WD) Setup Time	0.63	ns
t_{DH}	Input Data (WD) Hold Time	0.20	ns
t_{CKQ1}	Clock High to New Data Valid on RD (flow-through)	2.77	ns
t_{CKQ2}	Clock High to New Data Valid on RD (pipelined)	1.50	ns
t_{RCKEF}	RCLK High to Empty Flag Valid	2.94	ns
t_{WCKFF}	WCLK High to Full Flag Valid	2.79	ns
t_{CKAF}	Clock High to Almost Empty/Full Flag Valid	10.71	ns
t_{RSTFG}	RESET Low to Empty/Full Flag Valid	2.90	ns
t_{RSTAF}	RESET Low to Almost Empty/Full Flag Valid	10.60	ns
t_{RSTBQ}	RESET Low to Data Out LOW on RD (flow-through)	1.68	ns
	RESET Low to Data Out LOW on RD (pipelined)	1.68	ns
t_{REMRSTB}	RESET Removal	0.51	ns
t_{RECRSTB}	RESET Recovery	2.68	ns
t_{MPWRSTB}	RESET Minimum Pulse Width	0.68	ns
t_{CYC}	Clock Cycle Time	6.24	ns
F_{MAX}	Maximum Frequency for FIFO	160	MHz

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

1.2 V DC Core Voltage

Table 2-107 • FIFO

Worst Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, $V_{CC} = 1.14\text{ V}$

Parameter	Description	Std.	Units
t_{ENS}	REN, WEN Setup Time	3.44	ns
t_{ENH}	REN, WEN Hold Time	0.26	ns
t_{BKS}	BLK Setup Time	0.30	ns
t_{BKH}	BLK Hold Time	0.00	ns
t_{DS}	Input Data (DI) Setup Time	1.30	ns
t_{DH}	Input Data (DI) Hold Time	0.41	ns
t_{CKQ1}	Clock High to New Data Valid on RD (flow-through)	5.67	ns
t_{CKQ2}	Clock High to New Data Valid on RD (pipelined)	3.02	ns
t_{RCKEF}	RCLK High to Empty Flag Valid	6.02	ns
t_{WCKFF}	WCLK High to Full Flag Valid	5.71	ns
t_{CKAF}	Clock High to Almost Empty/Full Flag Valid	22.17	ns
t_{RSTFG}	RESET LOW to Empty/Full Flag Valid	5.93	ns
t_{RSTAF}	RESET LOW to Almost Empty/Full Flag Valid	21.94	ns
t_{RSTBQ}	RESET LOW to Data Out Low on RD (flow-through)	3.41	ns
	RESET LOW to Data Out Low on RD (pipelined)	4.09	3.41
t_{REMRSTB}	RESET Removal	1.02	ns
t_{RECRSTB}	RESET Recovery	5.48	ns
t_{MPWRSTB}	RESET Minimum Pulse Width	1.18	ns
t_{CYC}	Clock Cycle Time	10.90	ns
F_{MAX}	Maximum Frequency for FIFO	92	MHz

Note: For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

UC36	
Pin Number	AGLN010 Function
A1	IO21RSB1
A2	IO18RSB1
A3	IO13RSB1
A4	GDC0/IO00RSB0
A5	IO06RSB0
A6	GDA0/IO04RSB0
B1	GEC0/IO37RSB1
B2	IO20RSB1
B3	IO15RSB1
B4	IO09RSB0
B5	IO08RSB0
B6	IO07RSB0
C1	IO22RSB1
C2	GEA0/IO34RSB1
C3	GND
C4	GND
C5	VCCIB0
C6	IO02RSB0
D1	IO33RSB1
D2	VCCIB1
D3	VCC
D4	VCC
D5	IO10RSB0
D6	IO11RSB0
E1	IO32RSB1
E2	FF/IO31RSB1
E3	TCK
E4	VPUMP
E5	TRST
E6	VJTAG
F1	IO29RSB1
F2	IO25RSB1
F3	IO23RSB1
F4	TDI

UC36	
Pin Number	AGLN010 Function
F5	TMS
F6	TDO

VQ100		VQ100		VQ100	
Pin Number	AGLN060 Function	Pin Number	AGLN060 Function	Pin Number	AGLN060 Function
1	GND	36	IO61RSB1	71	GBB2/IO27RSB0
2	GAA2/IO51RSB1	37	VCC	72	IO26RSB0
3	IO52RSB1	38	GND	73	GBA2/IO25RSB0
4	GAB2/IO53RSB1	39	VCCIB1	74	VMV0
5	IO95RSB1	40	IO60RSB1	75	GNDQ
6	GAC2/IO94RSB1	41	IO59RSB1	76	GBA1/IO24RSB0
7	IO93RSB1	42	IO58RSB1	77	GBA0/IO23RSB0
8	IO92RSB1	43	IO57RSB1	78	GBB1/IO22RSB0
9	GND	44	GDC2/IO56RSB1	79	GBB0/IO21RSB0
10	GFB1/IO87RSB1	45*	GDB2/IO55RSB1	80	GBC1/IO20RSB0
11	GFB0/IO86RSB1	46	GDA2/IO54RSB1	81	GBC0/IO19RSB0
12	VCOMPLF	47	TCK	82	IO18RSB0
13	GFA0/IO85RSB1	48	TDI	83	IO17RSB0
14	VCCPLF	49	TMS	84	IO15RSB0
15	GFA1/IO84RSB1	50	VMV1	85	IO13RSB0
16	GFA2/IO83RSB1	51	GND	86	IO11RSB0
17	VCC	52	VPUMP	87	VCCIB0
18	VCCIB1	53	NC	88	GND
19	GEC1/IO77RSB1	54	TDO	89	VCC
20	GEB1/IO75RSB1	55	TRST	90	IO10RSB0
21	GEB0/IO74RSB1	56	VJTAG	91	IO09RSB0
22	GEA1/IO73RSB1	57	GDA1/IO49RSB0	92	IO08RSB0
23	GEA0/IO72RSB1	58	GDC0/IO46RSB0	93	GAC1/IO07RSB0
24	VMV1	59	GDC1/IO45RSB0	94	GAC0/IO06RSB0
25	GNDQ	60	GCC2/IO43RSB0	95	GAB1/IO05RSB0
26	GEA2/IO71RSB1	61	GCB2/IO42RSB0	96	GAB0/IO04RSB0
27	FF/GEB2/IO70RSB1	62	GCA0/IO40RSB0	97	GAA1/IO03RSB0
28	GEC2/IO69RSB1	63	GCA1/IO39RSB0	98	GAA0/IO02RSB0
29	IO68RSB1	64	GCC0/IO36RSB0	99	IO01RSB0
30	IO67RSB1	65	GCC1/IO35RSB0	100	IO00RSB0
31	IO66RSB1	66	VCCIB0		
32	IO65RSB1	67	GND		
33	IO64RSB1	68	VCC		
34	IO63RSB1	69	IO31RSB0		
35	IO62RSB1	70	GBC2/IO29RSB0		

Note: *The bus hold attribute (hold previous I/O state in Flash*Freeze mode) is not supported for pin 45 in AGLN060-VQ100.

VQ100	
Pin Number	AGLN250 Function
1	GND
2	GAA2/IO67RSB3
3	IO66RSB3
4	GAB2/IO65RSB3
5	IO64RSB3
6	GAC2/IO63RSB3
7	IO62RSB3
8	IO61RSB3
9	GND
10	GFB1/IO60RSB3
11	GFB0/IO59RSB3
12	VCOMPLF
13	GFA0/IO57RSB3
14	VCCPLF
15	GFA1/IO58RSB3
16	GFA2/IO56RSB3
17	VCC
18	VCCIB3
19	GFC2/IO55RSB3
20	GEC1/IO54RSB3
21	GEC0/IO53RSB3
22	GEA1/IO52RSB3
23	GEA0/IO51RSB3
24	VMV3
25	GNDQ
26	GEA2/IO50RSB2
27	FF/GEA2/IO49RSB2
28	GEC2/IO48RSB2
29	IO47RSB2
30	IO46RSB2
31	IO45RSB2
32	IO44RSB2
33	IO43RSB2
34	IO42RSB2
35	IO41RSB2
36	IO40RSB2

VQ100	
Pin Number	AGLN250 Function
37	VCC
38	GND
39	VCCIB2
40	IO39RSB2
41	IO38RSB2
42	IO37RSB2
43	GDC2/IO36RSB2
44	GDB2/IO35RSB2
45	GDA2/IO34RSB2
46	GNDQ
47	TCK
48	TDI
49	TMS
50	VMV2
51	GND
52	VPUMP
53	NC
54	TDO
55	TRST
56	VJTAG
57	GDA1/IO33RSB1
58	GDC0/IO32RSB1
59	GDC1/IO31RSB1
60	IO30RSB1
61	GCB2/IO29RSB1
62	GCA1/IO27RSB1
63	GCA0/IO28RSB1
64	GCC0/IO26RSB1
65	GCC1/IO25RSB1
66	VCCIB1
67	GND
68	VCC
69	IO24RSB1
70	GBC2/IO23RSB1
71	GGB2/IO22RSB1
72	IO21RSB1

VQ100	
Pin Number	AGLN250 Function
73	GBA2/IO20RSB1
74	VMV1
75	GNDQ
76	GBA1/IO19RSB0
77	GBA0/IO18RSB0
78	GGB1/IO17RSB0
79	GGB0/IO16RSB0
80	GBC1/IO15RSB0
81	GBC0/IO14RSB0
82	IO13RSB0
83	IO12RSB0
84	IO11RSB0
85	IO10RSB0
86	IO09RSB0
87	VCCIB0
88	GND
89	VCC
90	IO08RSB0
91	IO07RSB0
92	IO06RSB0
93	GAC1/IO05RSB0
94	GAC0/IO04RSB0
95	GAB1/IO03RSB0
96	GAB0/IO02RSB0
97	GAA1/IO01RSB0
98	GAA0/IO00RSB0
99	GNDQ
100	VMV0

Revision / Version	Changes	Page
Revision 2 (Dec 2008) Product Brief Advance v0.4 Packaging Advance v0.3	The second table note in "IGLOO nano Devices" table was revised to state, "AGLN060, AGLN125, and AGLN250 in the CS81 package do not support PLLs. AGLN030 and smaller devices do not support this feature."	II
	The I/Os per package for CS81 were revised to 60 for AGLN060, AGLN125, and AGLN250 in the "I/Os Per Package" table.	II
	The "UC36" pin table is new.	4-2
Revision 1 (Nov 2008) Product Brief Advance v0.3	The "Advanced I/Os" section was updated to include wide power supply voltage support for 1.14 V to 1.575 V.	I
	The AGLN030 device was added to product tables and replaces AGL030 entries that were formerly in the tables.	VI
	The "I/Os Per Package" table was updated for the CS81 package to change the number of I/Os for AGLN060, AGLN125, and AGLN250 from 66 to 64.	II
	The "Wide Range I/O Support" section is new.	1-8
	The table notes and references were revised in Table 2-2 • Recommended Operating Conditions ¹ . VMV was included with VCCI and a table note was added stating, "VMV pins must be connected to the corresponding VCCI pins. See <i>Pin Descriptions</i> for further information." Please review carefully.	2-2
	VJTAG was added to the list in the table note for Table 2-9 • Quiescent Supply Current (IDD) Characteristics, IGLOO nano Flash*Freeze Mode*. Values were added for AGLN010, AGLN015, and AGLN030 for 1.5 V.	2-7
	VCCI was removed from the list in the table note for Table 2-10 • Quiescent Supply Current (IDD) Characteristics, IGLOO nano Sleep Mode*.	2-8
	Values for I _{CCA} current were updated for AGLN010, AGLN015, and AGLN030 in Table 2-12 • Quiescent Supply Current (IDD), No IGLOO nano Flash*Freeze Mode ¹ .	2-8
	Values for PAC1 and PAC2 were added to Table 2-15 • Different Components Contributing to Dynamic Power Consumption in IGLOO nano Devices and Table 2-17 • Different Components Contributing to Dynamic Power Consumption in IGLOO nano Devices.	2-10, 2-11
	Table notes regarding wide range support were added to Table 2-21 • Summary of Maximum and Minimum DC Input and Output Levels.	2-19
	1.2 V LVCMOS wide range values were added to Table 2-22 • Summary of Maximum and Minimum DC Input Levels and Table 2-23 • Summary of AC Measuring Points.	2-19, 2-20
	The following table note was added to Table 2-25 • Summary of I/O Timing Characteristics—Software Default Settings and Table 2-26 • Summary of I/O Timing Characteristics—Software Default Settings: "All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range, as specified in the JESD8-B specification."	2-21
	3.3 V LVCMOS Wide Range and 1.2 V Wide Range were added to Table 2-28 • I/O Output Buffer Maximum Resistances ¹ and Table 2-30 • I/O Short Currents IOSH/IOSL.	2-23, 2-24



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